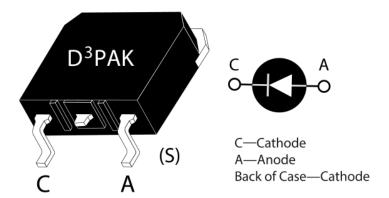


APT75DQ60SG Ultrafast Soft Recovery Rectifier Diode

1 Product Overview

This section outlines the product overview for the APT75DQ60SG device.



1.1 Features

The following are key features of the APT75DQ60SG device:

- Ultrafast recovery times
- Soft recovery characteristics
- Low forward voltage
- Low leakage current
- Avalanche energy rated
- RoHS compliant

1.2 Benefits

The following are benefits of the APT75DQ60SG device:

- High switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

1.3 Applications

The APT75DQ60SG device is designed for the following applications:

- Power factor correction (PFC)
- Anti-parallel diode
 - Switch-mode power supply
 - Inverters/converters
 - Motor controllers
- Freewheeling diode
 - Switch-mode power supply
 - Inverters/converters
- Snubber/clamp diode



2 Electrical Specifications

This section shows the electrical specifications for the APT75DQ60SG device.

2.1 Absolute Maximum Ratings

The following table lists the absolute maximum ratings for the APT75DQ60SG device.

All ratings: Tc = 25 °C unless otherwise specified.

Table 1 • Absolute Maximum Ratings

| Symbol | Parameter | Ratings | Unit |
|----------------------|---|------------|------|
| VR | Maximum DC reverse voltage | 600 | V |
| VRRM | Maximum peak repetitive reverse voltage | 600 | |
| VRWM | Maximum working peak reverse voltage | 600 | |
| I _{F(AV)} | Maximum average forward current (Tc = 108 °C, duty cycle = 0.5) | 75 | А |
| I _F (RMS) | RMS forward current | 117 | |
| IFSM | Non-repetitive forward surge current (T _J = 45 °C, 8.3 ms) | 600 | |
| Eavl | Avalanche energy (1 A, 40 mH) | 20 | mJ |
| Tı , Tstg | Operating and storage temperature range | -55 to 175 | °C |
| TL | Lead temperature for 10 seconds | 300 | |

The following table shows the thermal and mechanical characteristics of the APT75DQ60SG device.

Table 2 • Thermal and Mechanical Characteristics

| Symbol | Characteristic | Min | Тур | Max | Unit |
|--------|-------------------------------------|-----|------|------|------|
| Rejc | Junction-to-case thermal resistance | | | 0.34 | °C/W |
| Wt | Package weight | | 0.14 | | OZ |
| | | | 4.0 | | g |

2.2 Electrical Performance

The following table lists the static characteristics of the APT75DQ60SG device.

Table 3 • Static Characteristics

| Symbol | Characteristic | Test Conditions | Min | Тур | Max | Unit |
|--------|---------------------------------|---|-----|-----|-----|------|
| VF | Forward voltage | I _F = 75 A | | 2.0 | 2.5 | V |
| | | I _F = 150 A | | 2.4 | | _ |
| | | I _F = 75 A, T _J = 125 °C | | 1.7 | | _ |
| Irm | Maximum reverse leakage current | V _R = 600 V | | | 25 | μΑ |
| | | V _R = 600 V, T _J = 125 °C | | | 500 | _ |
| Cı | Junction capacitance | V _R = 200 V | | 110 | | pF |



2.3 Dynamic Characteristics

The following table lists the dynamic characteristics of the APT75DQ60SG device.

Table 4 • Dynamic Characteristics

| Symbol | Characteristic | Test Conditions | Min | Тур | Max | Unit |
|--------|----------------------------------|--|-----|------|-----|------|
| trr | Reverse recovery time | I _F = 1 A | | 29 | | ns |
| | | $di_F/dt = -100 A/\mu s$ | | | | |
| | | $V_R = 30 \text{ V}$ | | | | |
| | | T _J = 25 °C | | | | |
| trr | Reverse recovery time | I _F = 75 A | | 31 | | = |
| Qrr | Reverse recovery change | — di _F /dt = -200 A/μs — V _R = 400 V | | 55 | | nC |
| IRRM | Maximum reverse recovery current | Tc = 25 °C | | 4 | | Α |
| trr | Reverse recovery time | I _F = 75 A | | 140 | | ns |
| Qrr | Reverse recovery charge | | - | 650 | | nC |
| IRRM | Maximum reverse recovery current | Tc = 125 °C | | 9 | | Α |
| trr | Reverse recovery time | I _F = 75 A | | 90 | | ns |
| Qrr | Reverse recovery change | — di _F /dt = -1000 A/μs — V _R = 400 V | | 1300 | | nC |
| Irrm | Maximum reverse recovery current | Tc = 125 °C | | 27 | | Α |

2.4 Typical Performance Curves

This section shows the typical performance curves for the APT75DQ60SG device.

Figure 1 • Maximum Transient Thermal Impedance

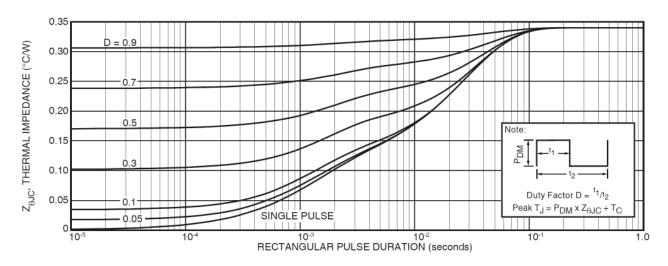




Figure 2 • Forward Current vs. Forward Voltage

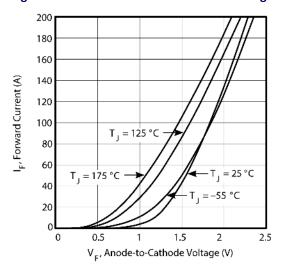


Figure 4 • Reverse Recovery Charge vs. Current Rate of Change

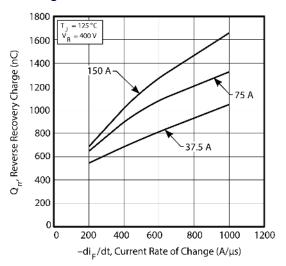


Figure 3 • RRT vs. Current Rate of Change

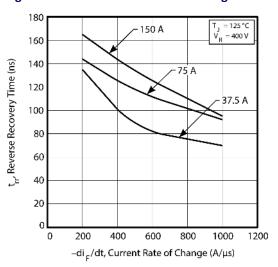


Figure 5 • Reverse Recovery Current vs. Current Rate of Change

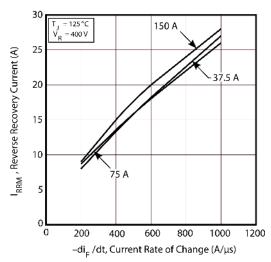




Figure 6 • Dynamic Parameters vs. Junction Temperature

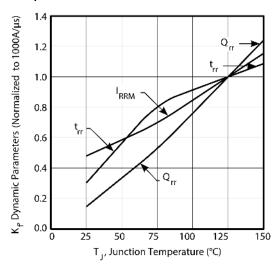


Figure 8 • Junction Capacitance vs. Reverse Voltage

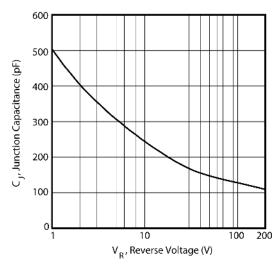
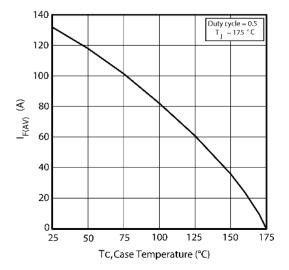


Figure 7 • Maximum Average Forward Current vs. Case Temperature

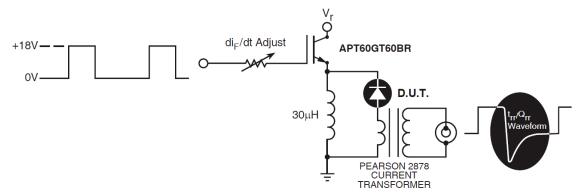




2.5 Reverse Recovery Overview

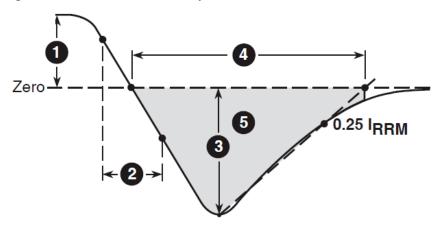
The following figure illustrates the diode test circuit for the APT75DQ60SG device.

Figure 9 • Diode Test Circuit



The following figure illustrates the diode reverse recovery waveform and definitions for the APT75DQ60SG device.

Figure 10 ● Diode Reverse Recovery Waveform and Definitions



- 1. IF—Forward conduction current.
- 2. di_F/dt—Rate of diode current change through zero crossing.
- 3. IRRM—Maximum reverse recovery current.
- 4. trr—Reverse recovery time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through IRRM and 0.25 IRRM passes through zero.
- 5. Qrr—Area under the curve defined by IRRM and trr.



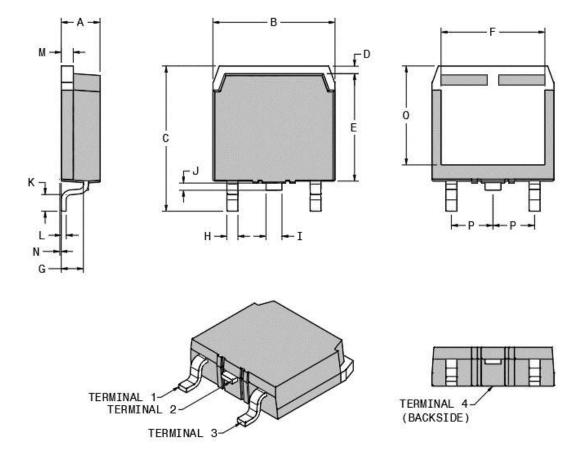
Package Specification 3

This section shows the package specification for the APT75DQ60SG device.

3.1

Package Outline Drawing
The following figure illustrates the TO-268 package outline of the APT75DQ60SG device.

Figure 11 • Package Outline Drawing





The following table lists the TO-268 dimensions and should be used in conjunction with the package outline drawing.

Table 5 • TO-268 Dimensions

| Symbol | Min (mm) | Max (mm) | Min (in.) | Max (in.) |
|------------|-------------------|----------|-------------|-----------|
| А | 4.90 | 5.10 | 0.193 | 0.201 |
| В | 15.85 | 16.20 | 0.624 | 0.638 |
| С | 18.70 | 19.10 | 0.736 | 0.752 |
| D | 1.00 | 1.25 | 0.039 | 0.049 |
| E | 13.80 | 14.00 | 0.543 | 0.551 |
| F | 13.30 | 13.60 | 0.524 | 0.535 |
| G | 2.70 | 2.90 | 0.106 | 0.114 |
| Н | 1.15 | 1.45 | 0.045 | 0.057 |
| I | 1.95 | 2.21 | 0.077 | 0.087 |
| J | 0.94 | 1.40 | 0.037 | 0.055 |
| К | 2.40 | 2.70 | 0.094 | 0.106 |
| L | 0.40 | 0.60 | 0.016 | 0.024 |
| М | 1.45 | 1.60 | 0.057 | 0.063 |
| N | 0.00 | 0.18 | 0.000 | 0.007 |
| 0 | 12.40 | 12.70 | 0.488 | 0.500 |
| Р | P 5.45 BSC (nom.) | | 0.215 BSC (| nom.) |
| Terminal 1 | Cathode | | | |
| Terminal 2 | Cathode | | | |
| Terminal 3 | Anode | | | |
| Terminal 4 | Cathode | | | |





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